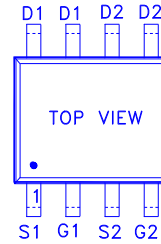
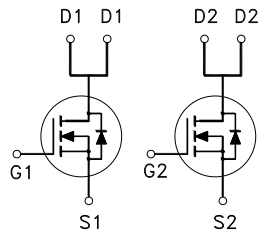


**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
100V	110mΩ	2.8A



G: GATE  
D: DRAIN  
S: SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	100	V
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$T_A = 25^\circ\text{C}$	$I_D$	2.8	A
	$T_A = 70^\circ\text{C}$		2.3	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	20	
Avalanche Current		$I_{AS}$	6	
Avalanche Energy	L = 1mH	$E_{AS}$	18	mJ
Power Dissipation <sup>3</sup>	$T_A = 25^\circ\text{C}$	$P_D$	2	W
	$T_A = 70^\circ\text{C}$		1.2	
Junction & Storage Temperature Range		$T_J, T_{stg}$	-55 to 150	$^\circ\text{C}$

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient <sup>2</sup>	$t \leq 10\text{s}$	$R_{\theta JA}$		62.5	$^\circ\text{C} / \text{W}$
Junction-to-Ambient <sup>2</sup>	Steady-State	$R_{\theta JA}$		85	
Junction-to-Case	Steady-State	$R_{\theta JC}$		35	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ .

<sup>3</sup>The Power dissipation is based on  $R_{\theta JA} t \leq 10\text{s}$  value.

**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

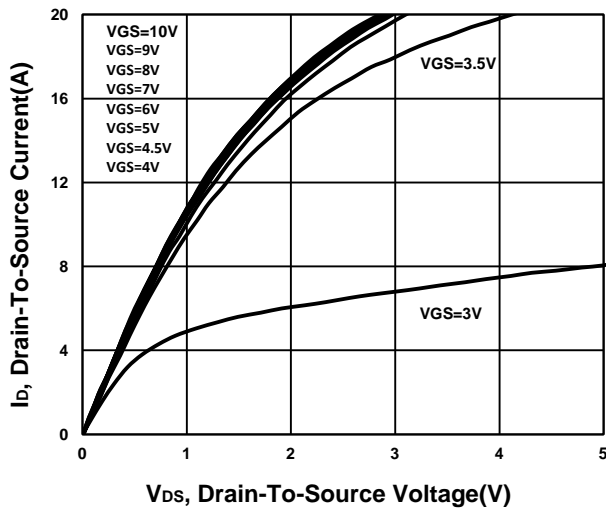
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.8	3	V
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}$			1	$\mu\text{A}$
		$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}, T_J = 70^\circ\text{C}$			10	

Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 2A$	82	120	m $\Omega$
		$V_{GS} = 10V, I_D = 2A$	78	110	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 10V, I_D = 2A$	10		S
<b>DYNAMIC</b>					
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	591		pF
Output Capacitance	$C_{oss}$		52		
Reverse Transfer Capacitance	$C_{rss}$		31		
Gate Resistance	$R_g$	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	1.6		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_{g(VGS=10V)}$	$V_{DS} = 50V, I_D = 2A$	13.5		nC
	$Q_{g(VGS=4.5V)}$		7.8		
Gate-Source Charge <sup>2</sup>	$Q_{gs}$		1.9		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		4.4		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$		$V_{DS} = 50V, I_D \cong 2A, V_{GS} = 10V, R_{GEN} = 6\Omega$	15	
Rise Time <sup>2</sup>	$t_r$	10			
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$	34			
Fall Time <sup>2</sup>	$t_f$	10			
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T<sub>J</sub> = 25 ° C)</b>					
Continuous Current	$I_S$			1.6	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 2A, V_{GS} = 0V$		1.2	V
Diode Reverse Recovery Time	$t_{rr}$	$I_F = 2A, di/dt = 100A/\mu s$	19		nS
Diode Reverse Recovery Charge	$Q_{rr}$		14		nC

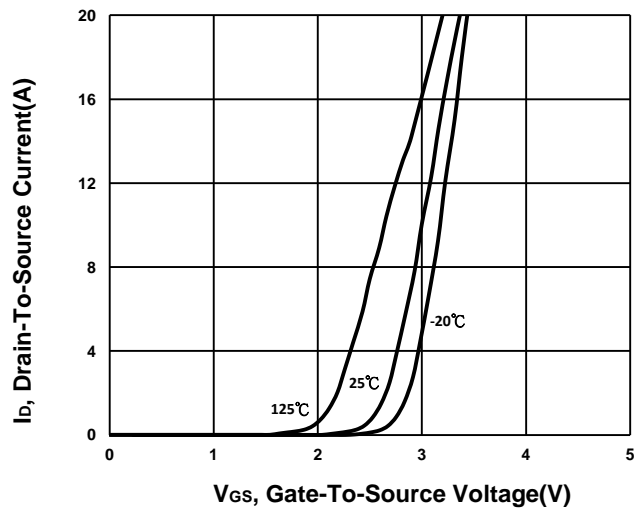
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

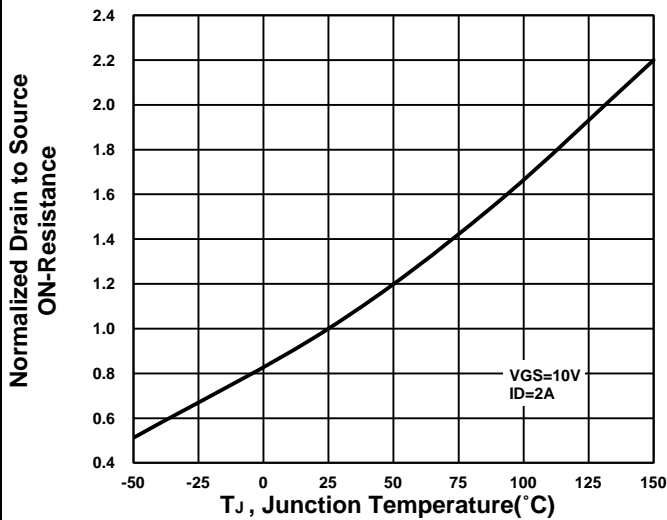
**Output Characteristics**



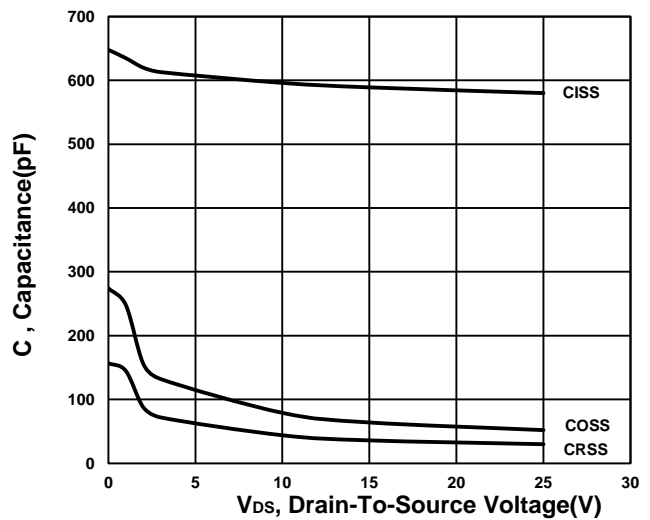
**Transfer Characteristics**



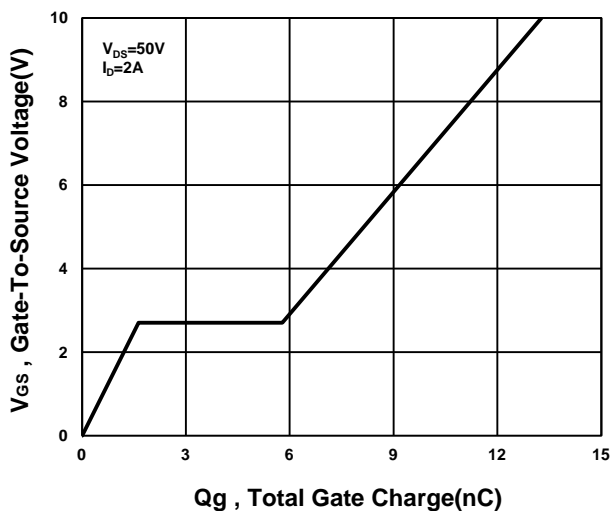
**On-Resistance VS Temperature**



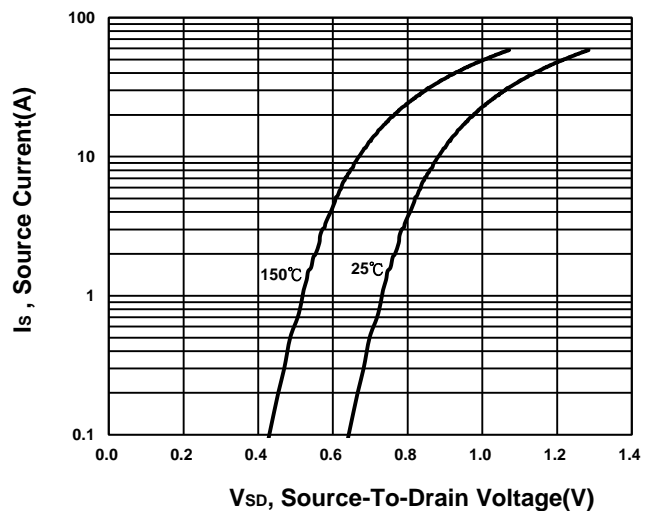
**Capacitance Characteristic**



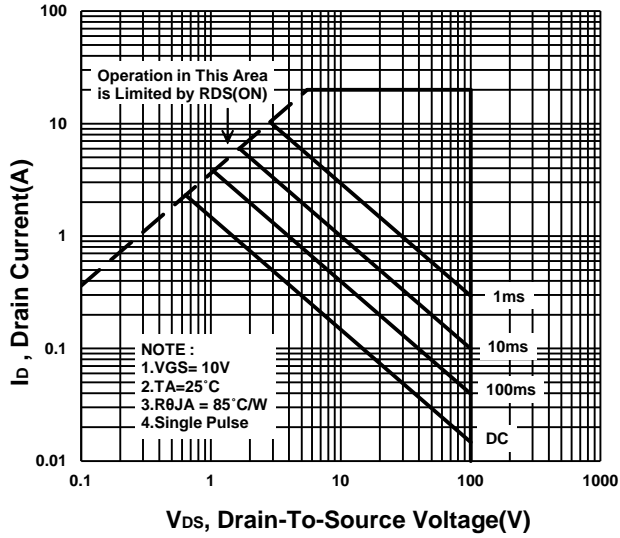
**Gate charge Characteristics**



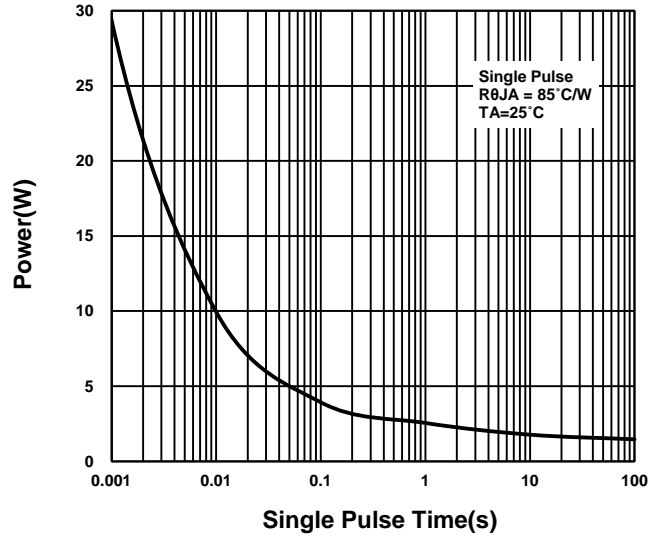
**Source-Drain Diode Forward Voltage**



**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**

